## Notice of References Cited

Application/Control No. 10/632,823	Applicant(s)/Patent Under Reexamination VENKATACHALAM, VIDYA		
Examiner	Art Unit		
Nathan Bloom	2609	Page 1 of 1	

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,151,406	11-2000	Chang et al.	382/147
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	H	US-			
	1	US-			
	Ļ	US-		•	
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	EP 741290 A1	11-1996	European Patent	VERCRUYSSE, MICHEL	
	0					,
	Р	•				
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

	NON-TAILNI DOCUMENTS		
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U	Bahlmann et al., "Artificial Neural Networks for Automated Quality Control of Textile Seams", Pattern Recognition Vol. 32 number 6 pp. 1049-1060, June 1999	
	<b>v</b>	Chin et al., "Model-Based Recognition in Robot Vision", ACM, Computing Surveys Vol.18 No.1, March 1986	
	w	Song et al., "A New Approach for Line Recognition in Large-size Images Using Hough Transform", ICPR 2002 Vol.1, IEEE	
	x		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.